

<b>Notice of References Cited</b>	Application/Control No. 10/706,115	Applicant(s)/Patent Under Reexamination LOOK, KEVIN T.	
	Examiner Steven J. Fulk	Art Unit 2891	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0124458	07-2004	Kothandaraman, Chandrasekharan	257/300
*	B	US-2005/0067670	03-2005	Hui, Frank Yauchee	257/529
*	C	US-4,219,836	08-1980	McElroy, David J.	257/390
*	D	US-6,911,360	06-2005	Li et al.	438/238
*	E	US-4,647,340	03-1987	Szluk et al.	438/281
*	F	US-6,703,680	03-2004	Toyoshima, Yoshiaki	257/529
*	G	US-2003/0122200	07-2003	Kamiya et al.	257/379
*	H	US-6,525,397	02-2003	Kalnitsky et al.	257/529
*	I	US-6,258,700	07-2001	Bohr et al.	438/467
*	J	US-4,872,140	10-1989	Graham et al.	365/96
*	K	US-4,238,839	12-1980	Redfern et al.	365/96
*	L	US-6,807,079	10-2004	Mei et al.	365/96
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.